



Description

The XPX4616XS uses advanced trench technology to provide excellent $R_{DS(ON)}$ and low gate charge . The complementary MOSFETs may be used to form a level shifted high side switch, and for a host of other applications.

General Features

- High power and current handing capability
- Lead free product is acquired
- Surface mount package

VDS = 30V, ID = 12A

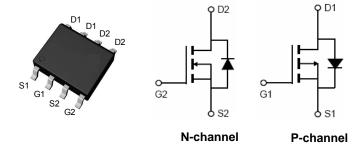
RDS(ON)= $11m\Omega$ (typ) @ VGS=10V

RDS(ON)= $15m\Omega$ (typ) @ VGS=4.5V

VDS = -30V, ID = -12A

RDS(ON)= $16m\Omega$ (typ) @ VGS=10V

RDS(ON)= $19m\Omega$ (typ) @ VGS=4.5V



| Product ID | Pack | Marking | Qty(PCS) |
|------------|-------|--------------------|----------|
| XPX4616XS | SOP-8 | XPX4616XS XXX YYYY | 3000 |

Absolute Maximum Ratings (T_C=25℃unless otherwise noted)

| Ola a l | P | Rat | 11 | | |
|--------------------------------------|---|------------|------------|------------|--|
| Symbol | Parameter | N-Ch | P-Ch | Units | |
| VDS | Drain-Source Voltage | 30 | -30 | V | |
| VGS | Gate-Source Voltage ±20 ±20 | | ±20 | V | |
| I _D @T _A =25℃ | Continuous Drain Current, V _{GS} @ 10V ¹ 12 -12 | | А | | |
| I _D @T _A =100℃ | Continuous Drain Current, V _{GS} @ 10V ¹ | 10 | -8 | Α | |
| IDM | Pulsed Drain Current ² | 52 | -45 | Α | |
| EAS | Single Pulse Avalanche Energy ³ | 22 | 45 | mJ | |
| IAS | Avalanche Current 21 -30 | | А | | |
| P _D @T _A =25°C | Total Power Dissipation ⁴ | 18 | 18 | W | |
| TSTG | Storage Temperature Range | -55 to 150 | -55 to 150 | $^{\circ}$ | |
| TJ | Operating Junction Temperature Range -55 to 150 -55 to 150 | | $^{\circ}$ | | |
| R₀JA | Thermal Resistance Junction-Ambient ¹ | 55 | | °C/W | |
| R₀JA | Thermal Resistance Junction-Ambient¹-(t<=10sec) | 5 | | °C/W | |



Electrical Characteristics (T_c=25℃unless otherwise noted)

| Symbol | Parameter | Conditions | Min. | Тур. | Max. | Unit |
|---------------------|--|--|------|------|------|-------|
| BVDSS | Drain-Source Breakdown Voltage | V _{GS} =0V , I _D =250uA | 30 | 32.5 | | V |
| RDS(ON) | Static Drain-Source On-Resistance ² | V _{GS} =10V , I _D =10A | | 11 | 16 | mΩ |
| T (DO(ON) | Ciallo Brain Course on Neoleiane | V _{GS} =4.5V , I _D =8A | | 15 | 20 | 11122 |
| $V_{\text{GS(th)}}$ | Gate Threshold Voltage | $V_{GS}=V_{DS}$, I_{D} =250uA | 1.0 | 1.6 | 2.5 | V |
| Inss | Drain-Source Leakage Current | V _{DS} =24V , V _{GS} =0V , T _J =25°C | | | 1 | uA |
| 1000 | | V _{DS} =24V , V _{GS} =0V , T _J =55°C | | | 5 | |
| Igss | Gate-Source Leakage Current | V_{GS} =±20 V , V_{DS} =0 V | | | ±100 | nA |
| gfs | Forward Transconductance | V _{DS} =5V , I _D =10A | | 16 | | S |
| Rg | Gate Resistance | V _{DS} =0V , V _{GS} =0V , f=1MHz | | 2.5 | 5 | Ω |
| Qg | Total Gate Charge (4.5V) | | | 7.2 | | |
| Qgs | Gate-Source Charge | V _{DS} =20V , V _{GS} =4.5V , I _D =10A | | 1.4 | | nC |
| Q_{gd} | Gate-Drain Charge | | | 2.2 | | |
| Td(on) | Turn-On Delay Time | | | 4.1 | | |
| Tr | Rise Time | V_{DD} =15V , V_{GS} =10V , R_{G} =3.3 Ω , | | 9.8 | | ns |
| $T_{d(off)}$ | Turn-Off Delay Time | I _D =5A | | 15.5 | | 115 |
| Tf | Fall Time | | | 6.0 | | |
| Ciss | Input Capacitance | | | 816 | | |
| Coss | Output Capacitance | V _{DS} =15V , V _{GS} =0V , f=1MHz | | 81 | | pF |
| Crss | Reverse Transfer Capacitance | | | 65 | | |
| ls | Continuous Source Current ^{1,5} | V _G =V _D =0V , Force Current | | | 12 | Α |
| VsD | Diode Forward Voltage ² | V _{GS} =0V , I _S =1A , T _J =25°C | | | 1.2 | V |

Note:

- 1. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- $2\sqrt{1}$ The data tested by pulsed , pulse width $\leq 300 \text{us}$, duty cycle $\leq 2\%$
- 3. The EAS data shows Max. rating . The test condition is V_{DD} =25V, V_{GS} =10V,L=0.1mH,I_{AS}=12A
- $5_{\text{\tiny N}}$ The data is theoretically the same as I_D and I_{DM} , in real applications, should be limited by total power dissipation.



Electrical Characteristics (T_c=25 ℃ unless otherwise noted)

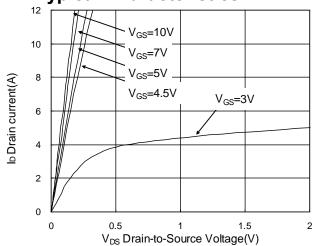
| Symbol | Parameter | Conditions | Min. | Тур. | Max. | Unit | |
|---------------------|--|--|------|------|------|------|--|
| BVDSS | Drain-Source Breakdown Voltage | V _{GS} =0V , I _D =-250uA | -30 | -33 | | V | |
| Rds(on) | Static Drain-Source On-Resistance ² | V _{GS} =-10V , I _D =-7A | | 16 | 19 | mΩ | |
| T (D3(ON) | | V _{GS} =-4.5V , I _D =-5A | | 19 | 30 | | |
| $V_{GS(th)}$ | Gate Threshold Voltage | V_{GS} = V_{DS} , I_D =-250uA | -1.0 | | -2.5 | V | |
| Ipss | Drain Course Lookers Current | V _{DS} =-24V , V _{GS} =0V , T _J =25°C | | | 1 | | |
| 1055 | Drain-Source Leakage Current | V _{DS} =-24V , V _{GS} =0V , T _J =55°C | | | 5 | uA | |
| Igss | Gate-Source Leakage Current | V_{GS} =±20 V , V_{DS} =0 V | | | ±100 | nA | |
| gfs | Forward Transconductance | V _{DS} =-5V , I _D =-7A | | 15 | | S | |
| Rg | Gate Resistance | V _{DS} =0V , V _{GS} =0V , f=1MHz | | 15 | 30 | | |
| Qg | Total Gate Charge (-4.5V) | | | 9.8 | | | |
| Qgs | Gate-Source Charge | V _{DS} =-20V , V _{GS} =-4.5V , I _D =-7A | | 2.2 | | nC | |
| Qgd | Gate-Drain Charge | | | 3.4 | | | |
| Td(on) | Turn-On Delay Time | | | 16.4 | | | |
| Tr | Rise Time | V_{DD} =-15V , V_{GS} =-10V , R_{G} =3.3 , | | 20.2 | | ns | |
| T _{d(off)} | Turn-Off Delay Time | | | 55 | | 115 | |
| T _f | Fall Time | | | 10 | | | |
| Ciss | Input Capacitance | | | 985 | | | |
| Coss | Output Capacitance | V _{DS} =-15V , V _{GS} =0V , f=1MHz | | 148 | | pF | |
| Crss | Reverse Transfer Capacitance | | | 115 | | | |
| ls | Continuous Source Current ^{1,5} | V _G =V _D =0V , Force Current | | | -12 | Α | |
| VsD | Diode Forward Voltage ² | V _{GS} =0V , I _S =-1A , T _J =25°C | | | -1.2 | V | |

Note:

- 1. The data tested by surface mo unted on a 1 inch² FR-4 board with 2OZ copper.
- 2. The data tested by pulsed , pulse width \leqq 300us , duty cycle \leqq 2%
- 3 The EAS data shows Max. rating . The test condition is V^{DD} =-25V,VGS=-10V,L=0.1mH,IAS=-12A
- 4. The power dissipation is limited by 150 $^{\circ}\mathrm{C}$ junction temperature
- 5 . The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.



N-Typical Characteristics



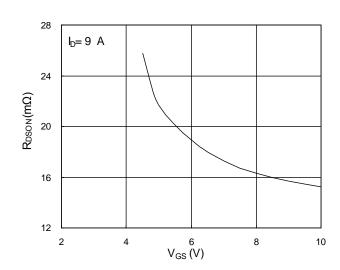


Fig.1 Typical Output Characteristics

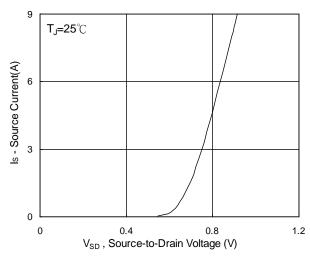


Fig.2 On-Resistance v.s Gate-Source

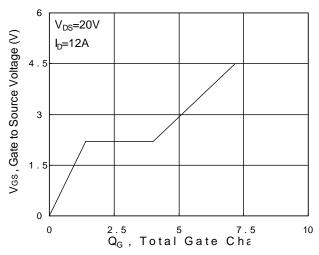


Fig.3 Forward Characteristics Of Reverse

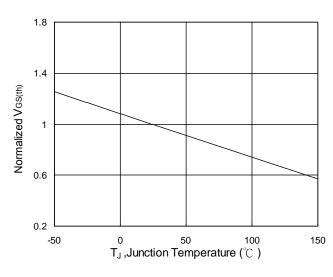


Fig.4 Gate-Charge characteristics

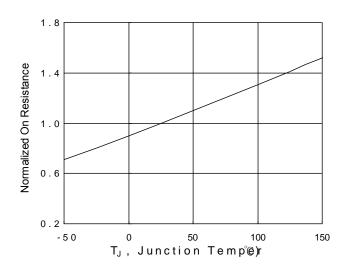
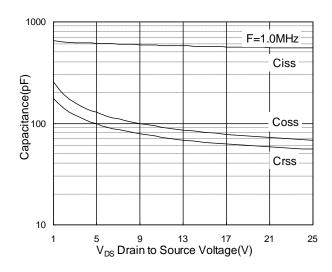


Fig.5 Normalized V_{GS(th)} v.s T_J

Fig.6 Normalized RDSON v.s TJ





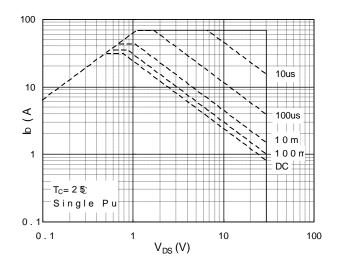


Fig.7 Capacitance

Fig.8 Safe Operating Area

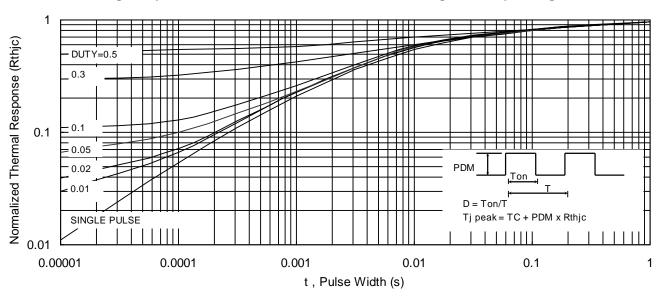


Fig.9 Normalized Maximum Transient Thermal Impedance

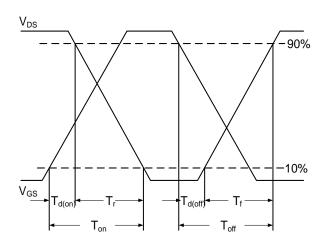


Fig.10 Switching Time Waveform

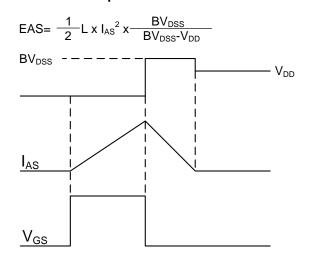


Fig.11 Unclamped Inductive Waveform



P-Typical Characteristics

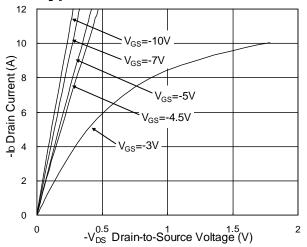


Fig.1 Typical Output Characteristics

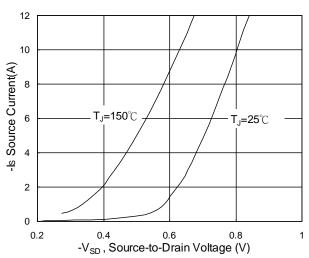


Fig.3 Forward Characteristics Of Reverse

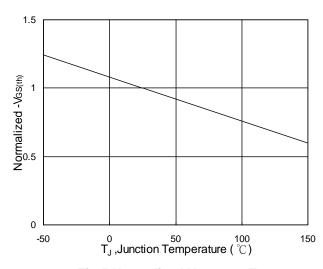


Fig.5 Normalized V_{GS(th)} v.s T_J

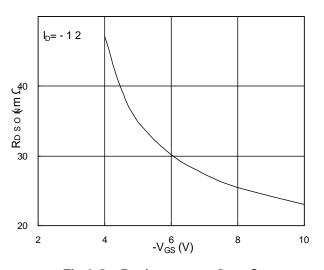


Fig.2 On-Resistance v.s Gate-Source

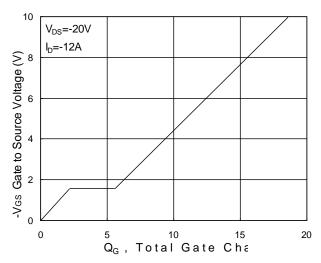


Fig.4 Gate-Charge Characteristics

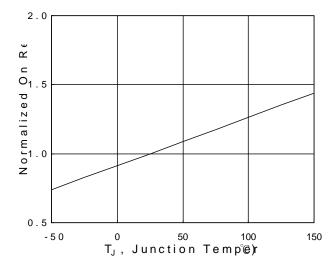
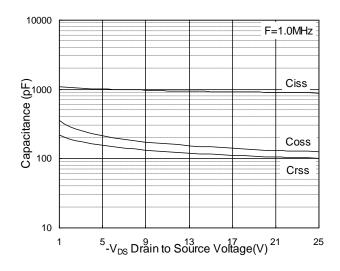


Fig.6 Normalized R_{DSON} v.s T_J





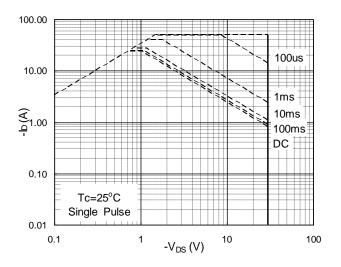


Fig.7 Capacitance

Fig.8 Safe Operating Area

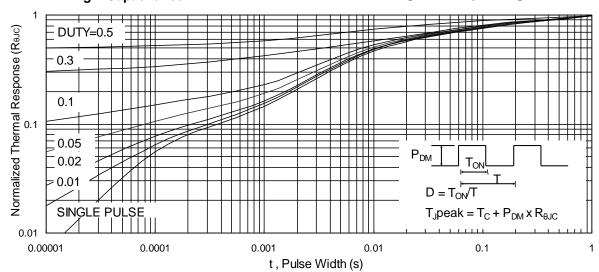
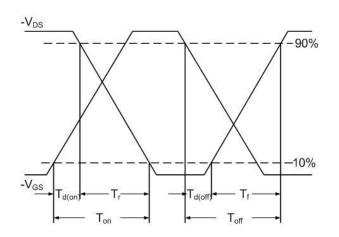
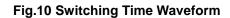


Fig.9 Normalized Maximum Transient Thermal Impedance





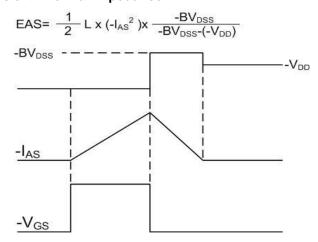
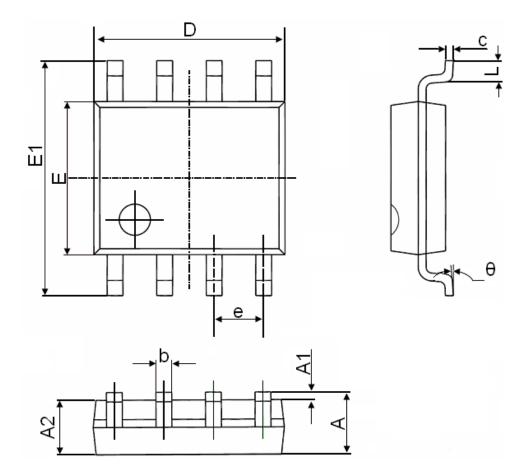


Fig.11 Unclamped Inductive Waveform



SOP-8 Package Information



| Cumbal | Dimensions | In Millimeters | Dimensions | s In Inches |
|--------|------------|----------------|------------|-------------|
| Symbol | Min. | Max. | Min. | Max. |
| Α | 1.350 | 1.750 | 0.053 | 0.069 |
| A1 | 0.100 | 0.250 | 0.004 | 0.010 |
| A2 | 1.350 | 1.550 | 0.053 | 0.061 |
| b | 0.330 | 0.510 | 0.013 | 0.020 |
| С | 0.170 | 0.250 | 0.006 | 0.010 |
| D | 4.700 | 5.100 | 0.185 | 0.200 |
| E | 3.800 | 4.000 | 0.150 | 0.157 |
| E1 | 5.800 | 6.200 | 0.228 | 0.244 |
| е | 1.270(BSC) | | 0.050(| BSC) |
| L | 0.400 | 1.270 | 0.016 | 0.050 |
| θ | 0° | 8° | 0° | 8° |



Flow (wave) soldering (solder dipping)

| Product | Peak Temperature | Dipping Time |
|----------------|-------------------|--------------|
| Pb device | 245℃±5℃ 5sec±1sec | |
| Pb-Free device | 260℃+0/-5℃ | 5sec±1sec |



This integrated circuit can be damaged by ESD UniverChip Corporation recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedure can cause damage. ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

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